

<b>Search Notes</b> 	<b>Application/Control No.</b>  10/640,558	<b>Applicant(s)/Patent under Reexamination</b>  VAN DUYN, PAUL D.
	<b>Examiner</b>  Jacob Y. Choi	<b>Art Unit</b>  2875

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
ALL	ALL	11/22/2005	JC